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## Reliability Data - Device MTBF/MTTF/FIT

Device: **CD8447DR2G**

Equivalent to wafer fab process: **BP STD LINEAR**

### Die Related Summary Data

Product Technology	Rej	Equivalent Device-Hours	MTBF/MTTF in Hours	FITS
BP STD LINEAR	0	3693073481	1603879366	0.62

#### Data is based on the following assumptions:

Activation Energy (constant) 0.7 *electron-volts*

Junction Temperature (25 - 175)  *Celsius*

One-sided Upper Confidence Level  *percent*

Calculate

Note: The temperature and confidence level may be adjusted to your requirements. Click the 'Calculate' button when set.

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